

**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

4105-74

SERIAL NO.

10/568,943

APPLICANT

CHO et al.

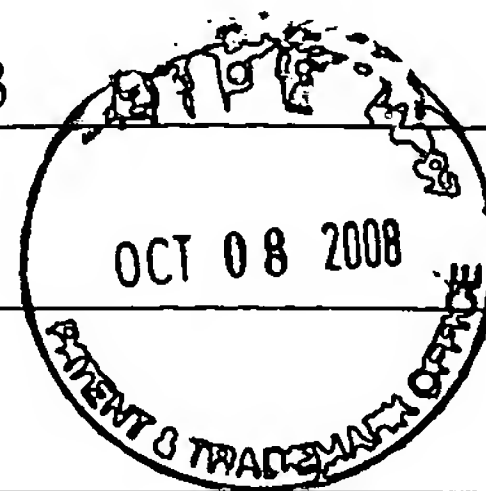
(Use several sheets if necessary)

FILING DATE

March 22, 2006

TC/A.U.

2627


U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2007/0014047	01/2007	Cho et al.			
	2006/0219655	11/2006	Cho et al.			
	2006/0245312	11/2006	Maeda et al.			
	2006/0182004	08/2006	Maeda et al.			
	2004/0263185	12/2004	Cho et al.	324	636	
	2004/0114913	06/2004	Kume	386	125	
	2004/0027935	02/2004	Cho et al.	369	126	
	2003/0021213	01/2003	Hagiwara, Yoshiaki	369	101	
	2,872,529	02/1959	Hollmann et al.			
	4,320,491	03/1982	Rustman, James C.	369	126	
	4,455,638	06/1984	Wilson	369	126	
	4,489,278	12/1984	Sawazaki, Norikazu	324	457	
	5,418,029	05/1995	Yamamoto et al.	428	64.2	
	5,481,527	01/1996	Kasanuki et al.	369	126	
	5,646,932	07/1997	Kuribayashi et al.	369	126	
	5,751,685	05/1998	Yi, You-Wen	369	126	
	5,777,977	07/1998	Fujiwara et al.	369	126	
	5,581,537	12/1996	Yamano et al.	369	126	
	5,914,920	06/1999	Yokogawa	369	275.3	
	5,946,284	08/1999	Chung et al.	369	126	
	5,985,404	11/1999	Yano et al.			
	6,477,132	11/2002	Azuma et al.	369	126	
	6,510,130	01/2003	Hayashi et al.	369	275.3	
	6,515,957	02/2003	Newns et al.	369	126	
	6,653,630	11/2003	Rosenman et al.	250	306	
	6,762,402	07/2004	Choi et al.	250	234	
	6,841,220	01/2005	Onoe et al.	428	66.7	
	6,912,193	06/2005	Cho et al.	369	126	
	6,965,545	11/2005	Hino et al.	369	13.54	
	7,065,033	06/2006	Onoe et al.	369	126	
	7,149,180	12/2006	Onoe et al.	369	276	

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO
08-075806	03/1996	JP			ABSTRACT	
644 426 A	10/1950	GB			ABSTRACT	
10-334525	12/1998	JP			ABSTRACT	
56-107338	08/1981	JP			ABSTRACT	

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

SERIAL NO.

4105-74

10/568,943

APPLICANT

CHO et al.

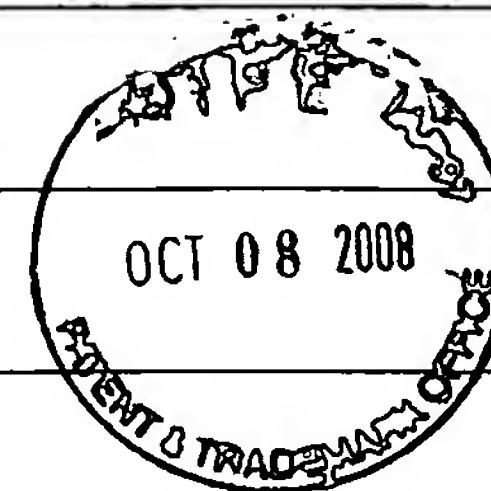
(Use several sheets if necessary)

FILING DATE

TC/A.U.

March 22, 2006

2627



OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

62th Japan Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2.

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,488,602	01/1996	Yamano et al.	369	126	
	5,808,977	09/1998	Koyanagi et al.	369	127	
	6,001,519	12/1999	Yang et al.			
	6,096,434	08/2000	Yano et al.			
	6,197,989	03/2001	Furukawa et al.	556	450	
	6,942,914	09/2005	Onoe et al.			
	7,212,484	05/2007	Maeda et al.			
	7,242,661	07/2007	Cho et al.			
	7,227,830	6/2007	Cho et al.			
	7,221,639	05/2007	Onoe et al.			
	7,218,600	05/2007	Cho et al.			
	7,151,739	12/2006	Cho et al.			
	2005/0122886	06/2005	Takahashi et al.	369	126	
	2005/0099895	05/2005	Maeda et al.	369	13.01	
	2005/0098532	05/2005	Onoe et al.	216	22	
	20050047288	03/2005	Maeda et al.	369	53.25	
	2004/0252621	12/2004	Cho et al.	369	126	
	2004/0105380	06/2004	Cho et al.	369	126	
	2004/0105373	06/2004	Maeda et al.	369	101	
	2004/0090903	05/2004	Cho et al.	369	126	
	2004/0042351	03/2004	Onoe et al.	369	13.01	
	2002/0131669	09/2002	Onoe et al.	385	14	
	2002/0118906	08/2002	Onoe	385	14	
	2002/0105249	08/2002	Yoshida et al.	310	311	
	2003/0186090	10/2003	Onoe et al.			

FOREIGN PATENT DOCUMENTS

						TRANSLATION	
DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS		YES	NO
57-200956	12/1982	JP				ABSTRACT	
1 484 256	09/1977	GB				ABSTRACT	
0 739 004	11/1996	EP				ABSTRACT	
1 154 422	11/2001	EP				ABSTRACT	

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

INFORMATION DISCLOSURE
CITATION

(Use several sheets if necessary)

Affy. Docket No.	Serial No.
4105-74	10/568,943
Applicant	
CHO et al.	
Filing Date	TC/A.U.
March 22, 2006	2627



U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,132,934 A	7/1992	Quate et al			
	5,724,336 A	3/1998	Morton			
	5,226,029 A	7/1993	Takanashi et al			
	6,850,480 B1	2/2005	Naito et al			
	5,985,404	11/1999	Yano et al			
	5,047,649	9/1991	Hodgson et al.			
	5,635,037	6/1997	Chu et al.			
	6,249,503	6/2001	Aratani			
	6,272,083	8/2001	Aratani			
	5,490,132	2/1996	Yagi et al.			
	5,412,641	5/1995	Shinjo et al.			

FOREIGN PATENT DOCUMENTS

						TRANSLATION	
DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS		YES	NO
55 139643 A	10/1980	JP				ABSTRACT	
0 398 656 A2	11/1990	EP				ABSTRACT	
1 091 355 A2	4/2001	EP				ABSTRACT	
57-200956	12/1982	JP				ABSTRACT	
11-176033	7/1999	JP				ABSTRACT	
0 480 183	4/1992	EP				ABSTRACT	
9-222430	8/1997	JP				ABSTRACT	
59-22250	2/1984	JP				ABSTRACT	
00/36608	6/2000	WO				ABSTRACT	
1 385 161	1/2004	EP				ABSTRACT	
9-511863	11/1997	JP				ABSTRACT	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

*Examiner		Date Considered	
-----------	--	-----------------	--

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Sheet 3 of 4

**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

SERIAL NO.

4105-74

10/568,943

APPLICANT

CHO et al.

(Use several sheets if necessary)

FILING DATE

TC/A.U.

March 22, 2006

2627


OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

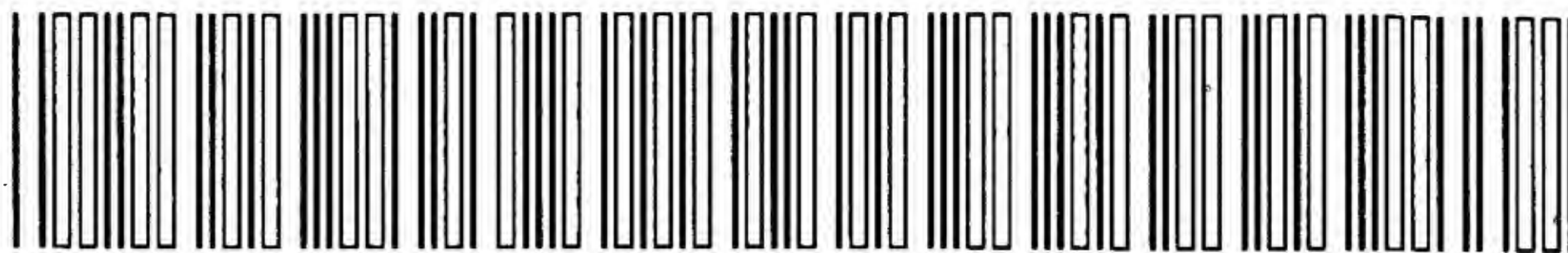
	Kazuta et al, "Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy", Journal of European Ceramic Society 21 (2001) 1581-1584.
	The Institution of Electrical Engineers, Stevenage, GB; 1 June 2002; Hiranaga et al, "Nano-sized inverted domain formation in stoichiometric LiTaO ₃ /single crystal using Scanning Nonlinear Dielectric Microscopy", XP002292217.
	Cho et al, "Scanning nonlinear dielectric microscopy with nanometer resolution", Journal of European Ceramic Society 21 (2001) 2131-2134.
	Cho et al., "Nano domain engineering using scanning nonlinear dielectric microscopy, October 29, 2001, IEE-NANO 2001, pages 352-357.

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

IDS REFERENCES



FOR